

DS1220AB/AD 16k Nonvolatile SRAM

FEATURES

- 10 years minimum data retention in the absence of external power
- Data is automatically protected during power loss
- Directly replaces 2k x 8 volatile static RAM or EEPROM
- Unlimited write cycles
- Low-power CMOS
- JEDEC standard 24-pin DIP package
- Read and write access times as fast as 100 ns
- Lithium energy source is electrically disconnected to retain freshness until power is applied for the first time
- Full ±10% V_{CC} operating range (DS1220AD)
- Optional ±5% V_{CC} operating range (DS1220AB)
- Optional industrial temperature range of -40°C to +85°C, designated IND

PIN ASSIGNMENT

A7	1 1	24 🔳	VCC
A6		23	A8
A5	3	22	A9
A4	4	21	WE
A3	■ 5	20 ■	ŌE
A2	6	19 🛮	A10
A1	□ 7	18	CE
A0	■ 8	17	DQ7
DQ0	1 9	₁₆ 🛮	DQ6
DQ1	1 0	15	DQ5
DQ2	1 11	14 🗖	DQ4
GND	1 2	13	DQ3
	1		

24-Pin ENCAPSULATED PACKAGE 720-mil EXTENDED

PIN DESCRIPTION

A0-A10	- Address Inputs
DQ0-DQ7	- Data In/Data Out
$\overline{\text{CE}}$	- Chip Enable
$\overline{ ext{WE}}$	- Write Enable
\overline{OE}	- Output Enable
V_{CC}	- Power (+5V)
GND	- Ground

DESCRIPTION

The DS1220AB and DS1220AD 16k Nonvolatile SRAMs are 16,384-bit, fully static, nonvolatile SRAMs organized as 2048 words by 8 bits. Each NV SRAM has a self-contained lithium energy source and control circuitry which constantly monitors $V_{\rm CC}$ for an out-of-tolerance condition. When such a condition occurs, the lithium energy source is automatically switched on and write protection is unconditionally enabled to prevent data corruption. The NV SRAMs can be used in place of existing $2k \times 8$ SRAMs directly conforming to the popular bytewide 24-pin DIP standard. The devices also match the pinout of the 2716 EPROM and the 2816 EEPROM, allowing direct substitution while enhancing performance. There is no limit on the number of write cycles that can be executed and no additional support circuitry is required for microprocessor interfacing.

ABSOLUTE MAXIMUM RATINGS*

Voltage on Any Pin Relative to Ground -0.3V to +6.0V

Operating Temperature

0°C to 70°C; -40°C to +85°C for IND parts

Storage Temperature

-40°C to +70°C; -40°C to +85°C for IND parts

Soldering Temperature +260°C for 10 seconds Caution: Do Not Reflow (Wave or Hand Solder Only)

RECOMMENDED DC OPERATING CONDITIONS

(T_A: See Note 10)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
DS1220AB Power Supply Voltage	V_{CC}	4.75	5.0	5.25	V	
DS1220AD Power Supply Voltage	V_{CC}	4.50	5.0	5.50	V	
Logic 1	V_{IH}	2.2		V_{CC}	V	
Logic 0	$V_{\rm IL}$	0.0		+0.8	V	

(T_A: See Note 10)

(V_{CC} =5V \pm 5% for DS1220AB)

DC ELECTRICAL CHARACTERISTICS

(V_{CC} =5V \pm 10% for DS1220AD)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Leakage Current	I_{IL}	-1.0		+1.0	μΑ	
I/O Leakage Current $\overline{CE} \ge V_{IH} \le V_{CC}$	I_{IO}	-1.0		+1.0	μΑ	
Output Current @ 2.4V	I_{OH}	-1.0			mA	
Output Current @ 0.4V	I_{OL}	2.0			mA	
Standby Current $\overline{CE} = 2.2V$	I_{CCS1}		5.0	10.0	mA	
Standby Current $\overline{CE} = V_{CC}-0.5V$	I_{CCS2}		3.0	5.0	mA	
Operating Current (Commercial)	I_{CC01}			75	mA	
Operating Current (Industrial)	I _{CCO1}			85	mA	
Write Protection Voltage (DS1220AB)	V_{TP}	4.5	4.62	4.75	V	
Write Protection Voltage (DS1220AD)	V_{TP}	4.25	4.37	4.5	V	

CAPACITANCE

 $(T_{\Delta} = 25^{\circ}C)$

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Capacitance	C _{IN}		5	10	pF	
Input/Output Capacitance	$C_{I/O}$		5	12	pF	

^{*} This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

(T_{A:} See Note 10)

(V_{CC} =5.0V \pm 5% for DS1220AB)

AC ELECTRICAL CHARACTERISTICS

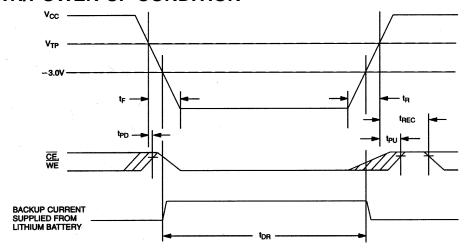
		DS1220AB-100		DS1220	OAB-120		
PARAMETER	SYMBOL	DS1220AD-100		DS1220AD-120		UNITS	NOTES
		MIN	MAX	MIN	MAX		
Read Cycle Time	t_{RC}	100		120		ns	
Access Time	t_{ACC}		100		120	ns	
OE to Output Valid	t_{OE}		50		60	ns	
CE to Output Valid	t_{CO}		100		120	ns	
$\overline{\text{OE}}$ or $\overline{\text{CE}}$ to Output Active	t_{COE}	5		5		ns	5
Output High Z from	t _{OD}		35		35	ns	5
Deselection	UD				33	113	
Output Hold from Address	t _{OH}	5		5		ns	
Change	чон			3		113	
Write Cycle Time	$t_{ m WC}$	100		120		ns	
Write Pulse Width	t_{WP}	75		90		ns	3
Address Setup Time	t_{AW}	0		0		ns	
Write Recovery Time	t_{WR1}	0		0		ns	12
	t_{WR2}	10		10		ns	13
Output High from WE	t_{ODW}		35		35	ns	5
Output Active from WE	t _{OEW}	5		5		ns	4
Data Setup Time	t_{DS}	40		50		ns	4
Data Hold Time	$t_{ m DH1}$	0		0		ns	12
	t _{DH2}	10		10		ns	13

AC ELECTRICAL CHARACTERISTICS

(cont'd)

PARAMETER	SYMBOL				0AB-200 0AD-200	UNITS	NOTES
		MIN	MAX	MIN	MAX	011110	110125
Read Cycle Time	t_{RC}	150		200		ns	
Access Time	t_{ACC}		150		200	ns	
OE to Output Valid	t_{OE}		70		100	ns	
CE to Output Valid	t_{CO}		150		200	ns	
$\overline{\text{OE}}$ or $\overline{\text{CE}}$ to Output Active	t_{COE}	5		5		ns	5
Output High Z from Deselection	t _{OD}		35		35	ns	5
Output Hold from Address Change	t _{OH}	5		5		ns	
Write Cycle Time	$t_{ m WC}$	150		200		ns	
Write Pulse Width	t_{WP}	100		150		ns	3
Address Setup Time	t_{AW}	0		0		ns	
Write Recovery Time	t_{WR1}	0		0		ns	12
	t_{WR2}	10		10		ns	13
Output High Z from WE	t_{ODW}		35		35	ns	5
Output Active from WE	t _{OEW}	5		5		ns	4
Data Setup Time	$t_{ m DS}$	60		50		ns	4
Data Hold Time	t _{DH1}	0		0		ns	12
	t _{DH2}	10		10		ns	13

POWER-DOWN/POWER-UP CONDITION



SEE NOTE 11

POWER-DOWN/POWER-UP TIMING

(T_A: See Note 10)

		- Д	1010			
PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
V_{CC} Fail Detect to \overline{CE} and \overline{WE} Inactive	t_{PD}			1.5	μs	11
V _{CC} slew from V _{TP} to 0V	t_{F}	300			μs	
V _{CC} slew from 0V to V _{TP}	t_{R}	300			μs	
V _{CC} Valid to $\overline{\text{CE}}$ and $\overline{\text{WE}}$ Inactive	t_{PU}			2	ms	
V _{CC} Valid to End of Write Protection	t_{REC}			125	ms	

 $(T_A = 25^{\circ}C)$

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Expected Data Retention Time	t_{DR}	10			years	9

WARNING:

Under no circumstances are negative undershoots, of any amplitude, allowed when device is in the battery backup mode.

NOTES:

- 1. WE is high for a read cycle.
- 2. $\overline{OE} = V_{IH}$ or V_{IL} . If $\overline{OE} = V_{IH}$ during write cycle, the output buffers remain in a high-impedance state.
- 3. t_{WP} is specified as the logical AND of \overline{CE} and \overline{WE} . t_{WP} is measured from the latter of \overline{CE} or \overline{CE} going low to the earlier of \overline{CE} or \overline{WE} going high.
- 4. t_{DS} is measured from the earlier of \overline{CE} or \overline{WE} going high.
- 5. These parameters are sampled with a 5 pF load and are not 100% tested.
- 6. If the $\overline{\text{CE}}$ low transition occurs simultaneously with or later than the $\overline{\text{WE}}$ low transition, the output buffers remain in a high-impedance state during this period.
- 7. If the $\overline{\text{CE}}$ high transition occurs prior to or simultaneously with the $\overline{\text{WE}}$ high transition, the output buffers remain in a high-impedance state during this period.

- 8. If WE is low or the WE low transition occurs prior to or simultaneously with the CE low transition, the output buffers remain in a high-impedance state during this period.
- 9. Each DS1220AB and each DS1220AD has a built-in switch that disconnects the lithium source until V_{CC} is first applied by the user. The expected t_{DR} is defined as accumulative time in the absence of V_{CC} starting from the time power is first applied by the user. This parameter is guaranteed by design and is not 100% tested.
- 10. All AC and DC electrical characteristics are valid over the full operating temperature range. For commercial products, this range is 0°C to 70°C. For industrial products (IND), this range is -40°C to +85°C.
- 11. In a power down condition the voltage on any pin may not exceed the voltage on V_{CC} .
- 12. t_{WR1} , t_{DH1} are measured from \overline{WE} going high.
- 13. t_{WR2}, t_{DH2} are measured from CE going high.
- 14. DS1220 modules are recognized by Underwriters Laboratory (U.L.®) under file E99151.

DC TEST CONDITIONS

Outputs Open Cycle = 200ns for Operating Current All Voltages Are Referenced to Ground

AC TEST CONDITIONS

Output Load: 100 pF + 1TTL Gate Input Pulse Levels: 0 - 3.0V

Timing Measurement Reference Levels

Input: 1.5V Output: 1.5V

Input Pulse Rise and Fall Times: 5ns

ORDERING INFORMATION

PART NUMBER	TEMPERATURE RANGE	SUPPLY TOLERANCE	PIN/PACKAGE	SPEED GRADE
DS1220AB-100	0°C to +70°C	5V ± 5%	24 / 720 EMOD	100ns
DS1220AB-100+	0°C to +70°C	5V ± 5%	24 / 720 EMOD	100ns
DS1220AB-100IND	-40°C to +85°C	5V ± 5%	24 / 720 EMOD	100ns
DS1220AB-100IND+	-40°C to +85°C	5V ± 5%	24 / 720 EMOD	100ns
DS1220AB-120	0°C to +70°C	5V ± 5%	24 / 720 EMOD	120ns
DS1220AB-120+	0°C to +70°C	5V ± 5%	24 / 720 EMOD	120ns
DS1220AB-150	0°C to +70°C	5V ± 5%	24 / 720 EMOD	150ns
DS1220AB-150+	0°C to +70°C	5V ± 5%	24 / 720 EMOD	150ns
DS1220AB-200	0°C to +70°C	5V ± 5%	24 / 720 EMOD	200ns
DS1220AB-200+	0°C to +70°C	5V ± 5%	24 / 720 EMOD	200ns
DS1220AB-200IND	-40°C to +85°C	5V ± 5%	24 / 720 EMOD	200ns
DS1220AB-200IND+	-40°C to +85°C	5V ± 5%	24 / 720 EMOD	200ns
DS1220AD-100	0°C to +70°C	5V ± 10%	24 / 720 EMOD	100ns
DS1220AD-100+	0°C to +70°C	5V ± 10%	24 / 720 EMOD	100ns
DS1220AD-100IND	-40°C to +85°C	5V ± 10%	24 / 720 EMOD	100ns
DS1220AD-100IND+	-40°C to +85°C	5V ± 10%	24 / 720 EMOD	100ns
DS1220AD-120	0°C to +70°C	5V ± 10%	24 / 720 EMOD	120ns
DS1220AD-120+	0°C to +70°C	5V ± 10%	24 / 720 EMOD	120ns
DS1220AD-150	0°C to +70°C	5V ± 10%	24 / 720 EMOD	150ns
DS1220AD-150+	0°C to +70°C	5V ± 10%	24 / 720 EMOD	150ns
DS1220AD-200	0°C to +70°C	5V ± 10%	24 / 720 EMOD	200ns
DS1220AD-200+	0°C to +70°C	5V ± 10%	24 / 720 EMOD	200ns
DS1220AD-200IND	-40°C to +85°C	5V ± 10%	24 / 720 EMOD	200ns
DS1220AD-200IND+	-40°C to +85°C	5V ± 10%	24 / 720 EMOD	200ns

⁺ Denotes lead-free/RoHS-compliant product.